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## Conference talks and Proceedings

### Invited talks

1. A. Erko, [Invited](#) speaker, Femtosecond Modular X-ray Spectrometer – Monochromator, [PhotonDiag 2018](#), International Workshop, DESY, Hamburg, September 2018

2. A. Erko, [Invited](#) speaker, Reflection zone plate wavelength –dispersive X-ray spectrometry EMAS 2017 15<sup>th</sup> EUROPEAN WORKSHOP on MODERN DEVELOPMENTS AND APPLICATIONS IN MICROBEAM ANALYSIS, 7 - 11 May 2017, Konstanz, Germany
3. A. Erko, [Invited](#) speaker, 2-Dimensional VLS Gratings for X-ray Spectroscopy and Monochromators with Femtosecond Time Resolution, International Conference on X-ray optics and Applications 2017, 18-21 April 2017, Yokohama, Japan
4. A. Erko, [Plenary](#) speaker, State-of-the-art X-ray optical systems and their fabrication, 13<sup>th</sup> International Conference of the European Society for Precision Engineering & Nanotechnology, 27-31 May 2013, Berlin, Germany.
5. A. Erko [Invited](#) speaker, 3-D Reflection Zone Plates for X-Ray Monochromatization and Spectroscopy, SRI 2012, The 17<sup>th</sup> Pan-American Synchrotron Radiation Instrumentation Conference June 19-21, 2013 at NIST, Gaithersburg, MD USA
6. A. Erko [Invited](#) speaker, Activities in Europe (SXR), “X-ray Optics for BES Light Source Facilities”, Basic Energy Sciences Workshop on X-ray Optics for BES Light Source Facilities Potomac, MD, March 27 – 29, 2013
7. A. Erko, [Invited](#) speaker, Novell Röntgenoptische Systeme für Spektroskopie und Monochromatoren. Prozessnahe Röntgenanalytik PRORA, 22-23 November 2013, Berlin-Adlershof.
8. A. Erko, [Invited](#) speaker, Nanometer optics and technology, First German-Russian conference on knowledge and technology transfer in science, St. Petersburg State University, Russia, 16-18 December, 2011
9. A. Erko, [Invited](#), Nanometer Optics Technologies at Helmholtz Centre Berlin. Joint final Conference of COST Actions IE0601 and MP0601: Wood Science for Cultural Heritage, 14-15/11/2011: Short Wavelength Laboratory Sources, 16-18/11/2011, Paris, France
10. A.- Erko, [Member of International Scientific Advisory Boat](#), “Recent Developments in FS Soft X-ray Spectroscopy”, E-MRS 2011 Symposia, Workshop on X-ray Technique for Advanced Materials: Nice, France, 9-14 May 2011
11. A. Erko, N. Langhoff, I. Höhn, M. Haschke, [Invited](#), Novel Wavelength-Dispersive Parallel X-ray Spectrometer, PRORA, 18-19 November 2011
12. A. Erko, A. Firsov, [Invited](#), Parallel fs spectrometer for soft x-rays, Workshop on X-ray Optics, Chernogolovka, Russia, 20-24 September 2010
13. A. Erko, [Invited](#) speaker, Integration of Diffraction Focussing Optics into RAY, SMEXOS: Simulation Methods for X-ray Optical Systems, February 24-25, 2009, Grenoble, France
14. A. Erko, [Invited](#) speaker, Hard X-Ray Microspectroscopy at BESSY II, SPIE Annual meeting Europe, Workshop: Challenge in Optics and Optoelectronics, Plaque, 23 April 2009, Czech Rep.
15. A. Erko, [Invited](#) speaker, X-ray micro/nano metrology at BESSY, 2-d School on Nanometrology, Chernogolovka, 28-30 May 2009, Russia
16. A. Erko, [Invited](#) speaker, [member of International Scientific Advisory Boat](#), Synthesized X-Ray Holographic Optics, 2-nd School and Workshop on X-Ray Micro and Nanoprobes (XMNP 2009), June 14-22, 2009, Italy
17. A. Erko, [Invited](#) speaker, A. Firsov, K. Holldack, Ultra-High Time Resolved XAS, XX Panhellenic Conference on Solid State Physics and Material Science, Thessaloniki, September 20-23, 2009, Greece
18. A. Erko, [Invited](#) speaker, A. Firsov, K. Holldack, New Developments in Femto-Second Soft X-rays Spectroscopy, SRI-2009, Melbourne, September 26 – October 2, 2009, Australia
19. A. Erko, [Invited](#) speaker, Moderne Röntgenoptiken für analytische Anwendungen an Synchrotron-beamlines und Labor, Fachtagung PRORA 2009, 26-27 November 2009, Berlin, Germany
20. A. Erko, [Invited](#) speaker, I. Zizak, X-Ray Micro-Spectroscopy at BESSY II, 54-th DAE Solid State Physics Symposium, MS University Baroda, Vadodara, December 14-18, 2009, India

21. A. Erko, *Member of International Scientific Advisory Board*, A. Firsov, K. Holldack “RZP monochromator for Femto-second XANES at BESSY II”, E-MRS 2009 Symposia, Workshop on X-ray Technique for Advanced Materials: Strasbourg, 8-12 June 2009
22. A. Erko, *Invited* speaker, Coherent Diffraction Optics for VUV and X-rays, 404 Wilhelm and Else Heraeus-Seminar “Matter in Coherent Light”, March 17-20, 2008, Physikzentrum Bad Honnef, Germany
23. A. Erko, *Invited*, A. Firsov, “High-resolution Diffraction X-Ray Optics”, Optics and Precision Engineering, Proceedings of the 2007 Sino-German High Level Expert Symposium on X-ray Optics, Shanghai, Optics and Precision Engineering, 12, (2007), 1816-1822
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2. A. Erko, A. Hafner, L. Anklamm, An. Firsov, Al. Firsov, H. Löchel, A. Sokolov, R. Gubzhokov “iZPS<sub>SEM</sub>: the new spectrometer for ultra-light elements”, PRORA Tagung, 11-13 November 2015, Berlin-Adlershof, Germany
3. M. Brzhezinskaya, A. Firsov, A. Erko, New Reflection Zone Plate Array Optics with Individual Depth Profiles for Ultra-fast X-Ray Applications, Abstract, 12<sup>th</sup> International conference SRI-2015, New York City, July 6-10, 2015
4. An. Firsov, Al. Firsov, H. Löchel, J. Probst, P. Loukas, A. Erko, Abstract, 3-Dimensional profiling for diffraction optical elements, SPIE, SPIE Optics + Optoelectronics, Prague, Czech Republic 13 - 16 April 2015, 9510-18
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